## Notice of References Cited Application/Control No. 10/785,416 Examiner Raleigh Chiu Applicant(s)/Patent Under Reexamination GORSKI ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0224799 A1	11-2004	Gorski et al.	473/520
*	В	US-2005/0003911 A1	01-2005	Yu, Kuo-Pin	473/521
*	С	US-2005/0009649 A1	01-2005	Okamoto, Koji	473/521
*	D	US-5,071,125	12-1991	Shen, Walter	473/521
*	Е	US-5,172,911 A	12-1992	Chang, Chen-Chung	473/521
*	F	US-5,242,724 A	09-1993	You, Chin-San	473/521
*	G	US-5,314,180 A	05-1994	Yamagishi et al.	473/521
*	н	US-5,860,878 A	01-1999	You, Chin-San	473/549
*	_	US-5,599,019 A	02-1997	Davis et al.	473/549
*	J	US-6,254,501 B1	07-2001	Chang, Kuo-Yi	473/545
*	К	US-6,471,607 B2	10-2002	Hsu, Young-Chen	473/523
*	L	US-6,663,515 B1	12-2003	Pai, Chin-Dong	473/521
*	М	US-6,685,583 B2	02-2004	Severa et al.	473/549

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification .
	N					
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	x	·				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.